

<b>Notice of References Cited</b>	Application/Control No. 10/529,207		Applicant(s)/Patent Under Reexamination KIDOKORO ET AL.	
	Examiner Jeffrey T. Palenik		Art Unit 1615	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,287,596	09-2001	Murakami et al.	424/464
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 98/02185	01-1998	Japan	Murakami et al.	A61K 9/20
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sigma-Aldrich website for mesh-metric conversions: <a href="http://www.sigmaaldrich.com/Area_of_Interest/Research_Essentials/Chemicals/Key_Resources/Technical_Library/Particle_Size_Conversion.html">http://www.sigmaaldrich.com/Area_of_Interest/Research_Essentials/Chemicals/Key_Resources/Technical_Library/Particle_Size_Conversion.html</a>
*	V	Machine translation for WO 98/02185 (which is published in Japanese)
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.